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检测  
TESTING  
CNAS L5785

## RF Exposure Evaluation Report

**Report No.:** CQASZ20200900999E-02  
**Applicant:** Wicked Audio, Inc  
**Address of Applicant:** 875 WEST 325 NORTH, LINDON, UT 84042, USA  
**Equipment Under Test (EUT):**  
**EUT Name:** Bluetooth headphone  
**Model No.:** WI-BT8350, WI-BT8351, WI-BT8352, WI-BT8353, WI-BT8354, WI-BT8355, 17LY62  
**Test Model No.:** WI-BT8350  
**Brand Name:** N/A  
**FCC ID:** 2AFM7WI-BT835X  
**Standards:** 47 CFR Part 1.1307  
47 CFR Part 2.1093  
KDB447498D01 General RF Exposure Guidance v06  
**Date of Receipt:** 2020-09-10  
**Date of Test:** 2020-09-10 to 2020-09-26  
**Date of Issue:** 2020-09-26  
**Test Result:** **PASS\***

\*In the configuration tested, the EUT complied with the standards specified above

**Tested By:** Martin Lee  
( Martin Lee )

**Reviewed By:** Sheek Luo  
( Sheek Luo )

**Approved By:** Jack Ai  
( Jack Ai )



## 1 Version

### Revision History Of Report

Report No.	Version	Description	Issue Date
CQASZ20200900999E-02	Rev.01	Initial report	2020-09-26

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### 3 General Information

#### 3.1 Client Information

Applicant:	Wicked Audio, Inc
Address of Applicant:	875 WEST 325 NORTH, LINDON, UT 84042, USA
Manufacturer:	Topway EM Enterprise Ltd.
Address of Manufacturer:	8F., Block B, Building 6, Baoneng Science and technology park, Qingxiang RD., Qinghu Industrial Park, Longhua New District, Shenzhen, GD, China 518109
Factory:	Shenzhen Jia Hua Li Dian Zi You Xian Gong Si
Address of Factory:	NO 101,201, BUILDING E, NEW INDUSTRIAL ZONE, SHENZHU ROAD, LIUYUE SHENKENG VILLAGE, HENGGANG, LONGGANG DISTRICT, SHENZHEN CHINA.

#### 3.2 General Description of EUT

Product Name:	Bluetooth headphone
Model No.:	WI-BT8350, WI-BT8351, WI-BT8352, WI-BT8353, WI-BT8354, WI-BT8355, 17LY62
Test Model No.:	WI-BT8350
Trade Mark:	N/A
Hardware Version:	V2.1
Software Version:	V1.0
EUT Power Supply:	lithium battery: DC3.7V, Charge by DC5V
Operation Frequency:	2402MHz~2480MHz
Bluetooth Version:	V5.0
Modulation Technique:	Frequency Hopping Spread Spectrum(FHSS)
Modulation Type:	GFSK, $\pi/4$ DQPSK, 8DPSK
Number of Channel:	79
Transfer Rate:	1Mbps/2Mbps/3Mbps
Hopping Channel Type:	Adaptive Frequency Hopping systems
Sample Type:	<input type="checkbox"/> Mobile <input checked="" type="checkbox"/> Portable <input type="checkbox"/> Fix Location
Test Software of EUT:	BK3256 RF Test_V1.3 (manufacturer declare )
Antenna Type:	PCB antenna
Antenna Gain:	1dBi

Note:

Model No.: WI-BT8350, WI-BT8351, WI-BT8352, WI-BT8353, WI-BT8354, WI-BT8355, 17LY62

Only the model WI-BT8350 was tested, since the electrical circuit design, layout, components used and internal wiring were identical for the above models, with difference being color of appearance and model name.

## 4 SAR Evaluation

### 4.1 RF Exposure Compliance Requirement

#### 4.1.1 Standard Requirement

According to KDB447498D01 General RF Exposure Guidance v06

##### 4.3.1. Standalone SAR test exclusion considerations

Unless specifically required by the published RF exposure KDB procedures, standalone 1-g head or body and 10-g extremity SAR evaluation for general population exposure conditions, by measurement or numerical simulation, is not required when the corresponding SAR Exclusion Threshold condition, listed below, is satisfied.

#### 4.1.2 Limits

The 1-g and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances  $\leq 50$  mm are determined by:

$$\left[ \frac{\text{max. power of channel, including tune-up tolerance, mW}}{\text{min. test separation distance, mm}} \right] \cdot \sqrt{f(\text{GHz})} \leq 3.0 \text{ for 1-g SAR and } \leq 7.5 \text{ for 10-g extremity SAR, where}$$

f(GHz) is the RF channel transmit frequency in GHz

Power and distance are rounded to the nearest mW and mm before calculation<sup>17</sup>

The result is rounded to one decimal place for comparison

The test exclusions are applicable only when the minimum test separation distance is  $\leq 50$  mm and for transmission frequencies between 100 MHz and 6 GHz. When the minimum test separation distance is  $< 5$  mm, a distance of 5 mm is applied to determine SAR test exclusion

### 4.1.3 EUT RF Exposure

#### 1) For BT

#### Measurement Data

GFSK mode				
Test channel	Peak Output Power (dBm)	Tune up tolerance (dBm)	Maximum tune-up Power	
			(dBm)	(mW)
Lowest(2402MHz)	-0.780	-1.5±1	-0.5	0.891
Middle(2441MHz)	-0.580	-1.5±1	-0.5	0.891
Highest(2480MHz)	-0.790	-1.5±1	-0.5	0.891
π/4DQPSK mode				
Test channel	Peak Output Power (dBm)	Tune up tolerance (dBm)	Maximum tune-up Power	
			(dBm)	(mW)
Lowest(2402MHz)	1.420	0.5±1	1.5	1.413
Middle(2441MHz)	1.630	1±1	2	1.585
Highest(2480MHz)	1.440	0.5±1	1.5	1.413
8DPSK mode				
Test channel	Peak Output Power (dBm)	Tune up tolerance (dBm)	Maximum tune-up Power	
			(dBm)	(mW)
Lowest(2402MHz)	1.720	1±1	2	1.585
Middle(2441MHz)	1.920	1±1	2	1.585
Highest(2480MHz)	1.750	1±1	2	1.585

Worst case: 8DPSK						
Channel	Maximum Peak Conducted Output Power (dBm)	Tune up tolerance (dBm)	Maximum tune-up Power		Calculated value	Exclusion threshold
			(dBm)	(mW)		
Lowest (2402MHz)	1.720	1±1	2	1.585	0.491	3.0
Middle (2441MHz)	1.920	1±1	2	1.585	0.495	
Highest (2480MHz)	1.750	1±1	2	1.585	0.499	
Conclusion: the calculated value ≤3.0, SAR is exempted.						

Remark: The Max Conducted Peak Output Power data refer to report Report No.: CQASZ20200900999E-01